

**Search Notes**

Application/Control No.

09/785,015

Examiner

Djenane M. Bayard

Applicant(s)/Patent under  
Reexamination

YANG ET AL.

Art Unit

2141

**SEARCHED**

Class	Subclass	Date	Examiner
709	230	6/3/2005	DB
370	229	6/7/2005	DB
370	235	6/7/2005	DB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
709	230	6/3/2005	DB
370	229/235	6/7/2005	db

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	6/2/2005	DB
Consulted with Le LUU	5/26/2005	DB
Consulted with Search mentor L. Donaghue	5/31/2005	DB
Inventor's name search	6/2/2005	DB
EIC Fast and focus search	4/4/2005	DB